The LCT-T4 measures components, including resistors, potentiometers, inductors, capacitors, diodes, dual diodes, transistors (including MOS), SCR's, regulators, LED's, and ESR.

For testing operation plug the component that you want to test into pins 1, 2 or 3 on either side of the DIL socket, then press the test button.

Specifications:

Resistor: ≤21000Ω
Resolution of Resistance Measurement: 0.1 Ohm
The Highest Measured Value: 50M ohms Provided Testing Current: Approx. 6mA
Capacitor: 25pF-100000μF
Inductance: 0.01mH - 20H
Working power: DC-9V (9 Volt block battery or 2 li-ion batteries to form 8.4V)
Standby current: 0.02μA
Shutdown Current: 20nA
Operating current: 25mA
Product Size: 7.2 x 6.25cm (L * W)

Description:

- Automatic detection of NPN and PNP transistors, N-channel and P-channel MOSFET, diodes (including dual diode), thyristors, transistors, resistors and capacitors and other components
- Measuring bipolar transistor current amplification factor and base-emitter threshold voltage.
- Automatic test out the pin element and displayed on the LCD
- Can be detected to determine the transistor emitter forward bias voltage of the transistor, MOSFET protection diode and the amplification factor of the base
- Reverse breakdown voltage is less than 4.5V, Zener diode can be identified.
- Measure the gate threshold voltage and gate capacitance of the MOSFET
- 2μF more capacitors can simultaneously measure the equivalent series resistance ESR values.
- Via the base-emitter threshold voltage and high current amplification factor to identify Darlington transistors.
- Can simultaneously measure two resistors and resistor symbol is displayed. Displayed on the right with a decimal value of 4.
- High test speed about 2 seconds (larger capacitor measurement can take up to 1 minute)
- One button operation, power-on test
- Auto power off function